This year at the International Test Conference 1998, we mourn the loss of one of our own; Dr. James Beausang was an active Program Committee member and a friend and colleague to many. James was Research and Development Manager for Test Compiler Products at Synopsys, Incorporated in Mountain View, California. He was also a mentor and teacher, leading by example and helping to develop outstanding engineers in EDA test technology.

James was an active and dedicated volunteer in the test community. He maintained several professional commitments to assist the community at large including: Chairman of the TTTC Web Initiatives Project; Program Committee member of ITC, ITCW and ETW; Panels Chairman of the TECS Workshop; and member of the IEEE P1500 Working Group.

Born in Ireland, James was the oldest brother in a close-knit family of eight children of Tom and Ita Beausang. From childhood James applied focus, organization and intensity to every aspect of his life. He had a deep social conscience and demonstrated his compassion for others in many ways. Throughout his life he displayed diverse interests and gifts, and had a strong commitment to family and friends. He excelled in math, music, English and woodwork. He played and took a keen interest in football. He also played the violin for many years, even performing as a soloist with the University College Dublin (UCD) Orchestra.

In 1982, after completing his B.E. in Electronic Engineering with First Class Honors at the University College Dublin, James journeyed to Rochester, New York, for graduate studies and overseas adventure. Just before his 21st birthday he started his studies at the University of Rochester with Professor Alex Albicki. There he made many friends who were to become professional colleagues as well. He spent five years as a student in Rochester, culminating with his thesis on Test Control for Self-Testable VLSI Chips.

James then joined AT&T Bell Labs, where he was consistently rated in the top tier of engineering talent. From Princeton, James moved on to Mountain View, California, in 1994 to join the Synopsys EDA test team.

Over the years, James made many fine contributions to the technology of test, ranging from his MSEE and Ph.D. studies at the University of Rochester, through his work at AT&T Bell Laboratories, to his work with the test team at Synopsys. He contributed to the success of the IEEE 1149.1 Boundary Scan standard, helping with its definition and revisions and developing boundary scan products while at AT&T. Once at Synopsys, he helped to define and develop one-pass scan synthesis, sophisticated hierarchical scan architecture techniques and boundary scan compliance checking.

James was a dedicated and consummate software engineer. He was a student of software design and good programming practice. He constantly strove for consistency, quality and robustness in software and algorithmic design. He also focused on use models that would allow designers to work intuitively and efficiently with EDA tools developed by his team.

Unfortunately, we will miss James’ further contributions, both as a professional in the test community and as a friend and colleague. We extend our sincere condolences to his family and friends at the loss of someone so special. And although we are forced to accept and acknowledge our own grief at losing him, we must also celebrate James’ many accomplishments in life and look beyond our sorrow. We wish Godspeed to you, James Beausang ... you are, and will continue to be, missed.